# Simple Bayesian Algorithms for Best-Arm Identification

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Bayesian Best-Arm Identification

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## 1 First Section

- Settings
- Algorithms

2 Numerical Experiments

## 3 Theoretical Results

Multi-Arm bandits has been researched for a long time. Typically, people use *Regret* as performance measure. However, here are still many cases that are not sensitive to regret. For example

- A/B tests
- Simulation Optimization (tuning)
- Oesign of Clinical Trials

In these cases, we want to identify the best arm within shorter trails. Maybe the best algorithms for regret is not the best for identification.

We consider the problem in *frequentist* setting, but the algorithm that we consider is *Bayesian* algorithm.

Suppose here is k arm with mean  $(\theta_1^*, \cdots, \theta_k^*)$ . At each time  $n \in \mathbb{N}$ , one choose design  $I_n \in \{1, 2, \cdots, k\}$  and observe  $Y_{n, I_n}$  as response.

 $Y_n \stackrel{\Delta}{=} (Y_{n,1}, \cdots, Y_{n,k})$  is independently across time. We focus on one dimensional exponential response, i.e.

$$p(y|\theta) = b(y) \exp(\theta T(y) - A(\theta)).$$
(1)

For convenience,  $T(\cdot)$  is strictly increasing  $\Rightarrow E[Y|\theta]$  is increasing of  $\theta$ . Let  $I^* = \arg \max_i \theta_i^*$  and suppose  $\theta_i \neq \theta_j \quad \forall i \neq j$ . Let  $\Pi_1$  be the prior distribution on parameter region  $\Theta$  ( $\theta^* \in \Theta$ ). Based on observation sequence ( $I_1, Y_{1,l_1}, \cdots, I_{n-1}, Y_{n-1,l_{n-1}}$ ), we have posterior measure  $Pi_n$  with density

$$\pi_n(\theta) = \frac{\pi(\theta)L_{n-1}(\theta)}{\int_{\Theta} \pi(\theta)L_{n-1}(\theta)d\theta}, \quad n \ge 2,$$
(2)

where

$$L_{n-1}(\theta) = \prod_{l=1}^{n-1} p(Y_{l,l_l}|\theta_{l_l})$$

is the likelihood.

To describe the algorithm and related results, we need following additional notations.

$$\bullet \quad \text{Advantage region } \Theta_i \stackrel{\Delta}{=} \bigg\{ \theta \in \Theta \bigg| \theta_i > \max_{j \neq i} \theta_j \bigg\}.$$

**2** Posterior Probability of *i*-th arm  $\alpha_{n,i} \stackrel{\Delta}{=} \prod_n (\Theta_i) = \int_{\Theta_i} \pi_n(\theta) d\theta$ .

- S Assigned Probability  $\psi_{n,i} \stackrel{\Delta}{=} \mathbb{P}(I_n = i | \mathcal{F}_{n-1})$
- Accumulated Effort  $\Psi_{n,i} \stackrel{\Delta}{=} \sum_{l=1}^{n} \psi_{n,i}$

**(**) Average Effort 
$$ar{\psi}_{n,i} = n^{-1} \Psi_{n,i}$$

At each cycle, we do the following things:

- **()** Calculate  $\alpha_i$ , let  $\hat{I}^* = \arg \max_i \alpha_i$  and  $\hat{J}^* = \arg \max_{i \neq \hat{I}^*} \alpha_j$
- 2 Toss a coin  $B \ bin(p)$ , p is a hyper-parameter
- 3 If B = 1 use  $\hat{I}^*$  otherwise use  $\hat{J}^*$
- Opdate posterior distribution

Define utility function  $u : \theta \to \mathbb{R}$  as continuous and strictly increasing function. Then we can define value function  $v_i(\vec{\theta} = \max_j u(j) - \max_{j \neq i} u(j))$ . Then define  $V_{n,i} = \mathbb{E}^{\prod_n}[v_i]$ .

- Calculate  $V_i$ , let  $\hat{I}^* = \arg \max_i V_i$  and  $\hat{J}^* = \arg \max_{j \neq \hat{I}^*} V_j$
- 2 Toss a coin  $B \ bin(p)$ , p is a hyper-parameter

**③** If 
$$B=1$$
 use  $\hat{I}^*$  otherwise use  $\hat{J}^*$ 

Update posterior distribution

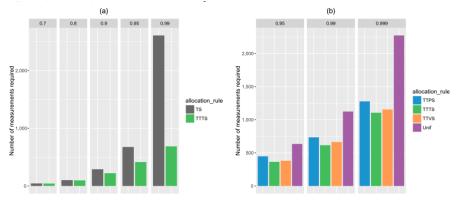
Likewise, we add additional sampling to TS, we get

- Calculate  $\alpha_i$  and sample  $\hat{I}$  according to  $\alpha_i$
- 2 Toss a coin B bin(p)
- $\textbf{ o If } B = 1 \text{ use } \hat{I} \text{ else sample } \hat{J} \text{ until } \hat{J} \neq \hat{I}$
- Opdate posterior distribution

Set  $\theta^* = (.1, .2, .3, .4, .5)$  and  $Y_{n,i}$  follows a binary distribution. We set hyper parameter p = 0.5 and observe how many times we need when confidence interval of optimal arm superseding a threshold, i.e.  $\max_i \alpha_{n,i} > c$ . We compare Top-Two methods with TS methods and uniformly testing

methods.

# Comparing with TS



Notes. (a) TS vs. top-two TS. (b) Comparison with uniform allocation.

## Allocations

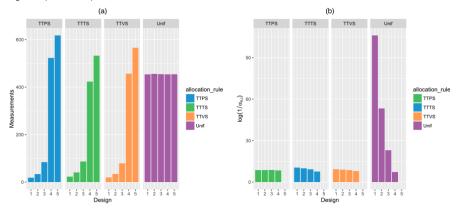


Figure 2. (Color online) Distribution of Measurements and Posterior Beliefs at Termination

Notes. (a) Measurements collected of each design. (b) Value of  $log(1/\alpha_{n,i})$  for each design *i*.

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## Main Theorems

We focus on convergence rate of  $\Pi_n(\Theta_{I^*}^c) = \sum_{i \neq I^*} \alpha_{n,i}$ , i.e. the convergence rate of false probability. We assume that  $\Theta = (\underline{\theta}, \overline{\theta})^k$ , i.e. a bounded rectangle and  $0 < \inf_{\theta \in \Theta} \pi_1(\theta) < \sup_{\theta \in \Theta} \pi_1(\theta) < \infty$  (regular prior). Moreover, we assume  $\sup_{\theta} |A'(\theta)| < \infty$ . Then, let we define following rates:

$$\bar{\psi}^{*} = \max_{\psi} \min_{\theta \in \Theta_{I^{*}}^{c}} \sum_{i=1}^{k} \psi_{i} d(\theta_{i}^{*} \| \theta_{i}), \qquad (3)$$

and

$$\Gamma_{\beta}^{*} = \max_{\psi:\psi_{I^{*}}=\beta} \min_{\theta\in\Theta_{I^{*}}^{c}} \sum_{i=1}^{k} \psi_{i} d(\theta_{i}^{*} \| \theta_{i}).$$
(4)

#### Theorem

There exist constants { $\Gamma_{\beta}^* > 0 : \beta \in (0,1)$ } such that  $\Gamma^* = \max_{\beta} \Gamma_{\beta}^*$  exists,  $\beta^* = \arg \max_{\beta} \Gamma_{\beta}^*$  is unique and the following properties satisfies with probability 1:

**1** Under Top-Two algorithms with parameter  $\beta^*$ ,

$$\lim_{n\to\infty}-\frac{1}{n}\log\Pi_n(\Theta_{I^*}^c).$$

Under any adaptive allocation rule,

$$\lim \sup_{n\to\infty} -\frac{1}{n} \log \prod_n (\Theta_{I^*}^c) \leq \Gamma^*.$$

#### Theorem

**1** Under Top Two algorithms, with parameter  $\beta \in (0, 1)$ ,

$$\lim_{n\to\infty} -\frac{1}{n}\log \prod_n (\Theta_{I^*}^c) = \Gamma_{\beta}^c \quad and \quad \lim_{n\to\infty} \bar{\psi}_{n,I^*} = \beta.$$

Under any adaptive allocation rule,

$$\lim \sup_{n \to \infty} -\frac{1}{n} \log \prod_n (\Theta_{I^*}^c) \leq \Gamma_{\beta}^*,$$

on any sample path with  $\lim_{n\to\infty} \bar{\psi}_{n,l^*} = \beta$ . **2**  $\Gamma^* \leq 2\Gamma^*_{\frac{1}{2}}$ .

These theorems show that  $\Pi(\Theta_{I^*}^c) = O(e^{-n\Gamma_{\beta}^*}).$ 

Let we denote  $a_n \doteq b_n$  if  $\frac{1}{n} \log(\frac{a_n}{b_n}) \rightarrow 0$ . For example,

 $a_n + b_n \stackrel{\cdot}{=} \max(a_n, b_n)$  and  $ca_n \stackrel{\cdot}{=} a_n$ , etc.

Then main theorem mainly shows that  $\prod_n (\Theta_{I^*}^c) \doteq e^{-n\Gamma_{\beta}^*}$  and cannot be faster than  $e^{-n\Gamma^*}$ .

Now we show the intuition behind this theorem by KL-divergence. Define  $d(\theta \| \theta') = \int \log(\frac{p(y|\theta)}{p(y|\theta')}) p(y|\theta) dv(y)$ , and

$$D_{\Psi}( heta, heta') = \sum_{i=1}^k \Psi_i d( heta_i, heta'_i),$$

which measures the average information gain using sampler  $\Psi$ .

# Intuition of Main Theorem

## We have following Proposition

#### Theorem

For any open set  $\tilde{\Theta} \in \Theta$ ,

$$\Pi_n(\tilde{\Theta}) \stackrel{\cdot}{=} \exp\left\{-n \inf_{\theta \in \tilde{\Theta}} D_{\bar{\psi}_n}(\theta^* \| \theta)\right\}.$$

Intuition:

$$\log(\frac{\pi_n(\theta)}{\pi_n(\theta^*)}) = \log(\frac{\pi_1(\theta)}{\pi_1(\theta^*)}) + \sum_{l=1}^{n-1} \log(\frac{p(Y_{l,i}|\theta)}{p(Y_{l,i}|\theta^*)}),$$

which is a random walk with drift  $\mathbb{E}\left[\log\left(\frac{p(Y_{l,i}|\theta)}{p(Y_{l,i}|\theta^*)}\right)\right]$  if the policy  $\psi_{n,i}$  converges to some  $\psi$ , then the drift is close to  $-D_{\psi}(\theta^*||\theta)$ .

Since we know  $\Pi_n(\Theta_{I^*}^c) \doteq \exp\left\{-n \inf_{\theta \in \Theta_{I^*}^c} D_{\bar{\psi}_n}(\theta^* \| \theta)\right\}$ , to find the fastest rate, we need to find

$$\max_{\psi}\min_{\theta\in\Theta_{I^*}^c}D_{\psi}(\theta^*\|\theta),$$

which is just  $\Gamma^*.$  Similarly,  $\Gamma^*_\beta$  is also defined in this way intuitively.



#### Danial Russo (2020)

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# The End

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